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**Laser-Based Irradiation Apparatus and Methods for
Monitoring the Dose-Rate Response of Semiconductor Devices**
Kevin M. Horn
SD-7021/S97,679

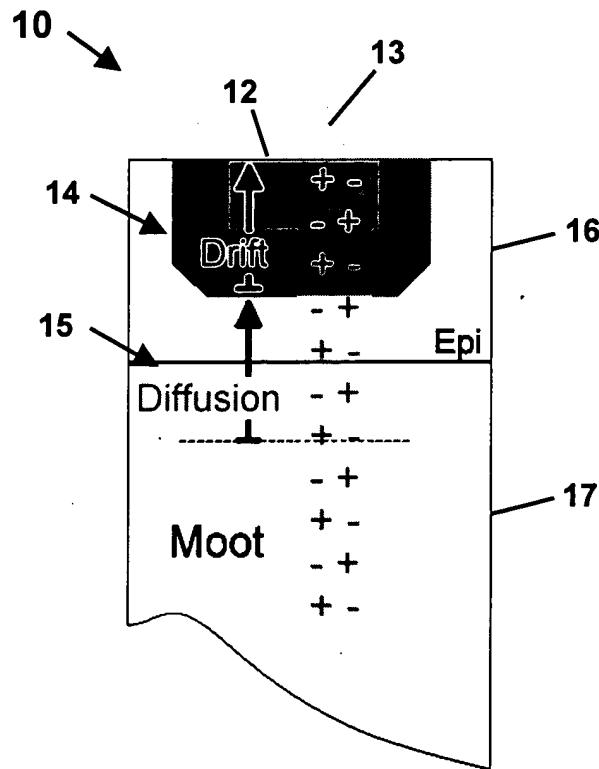


FIG. 1A

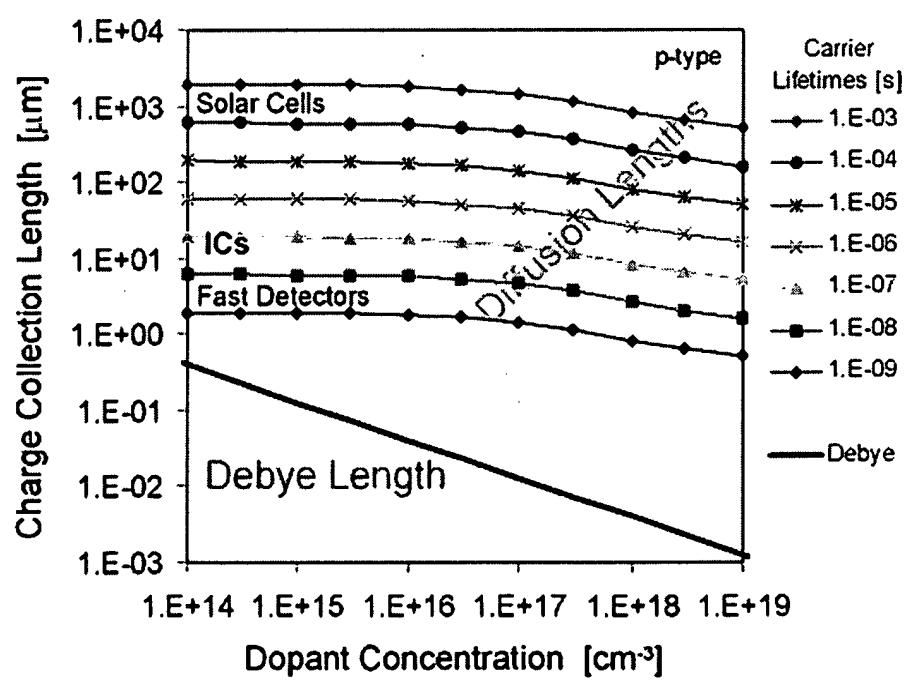


FIG. 2A

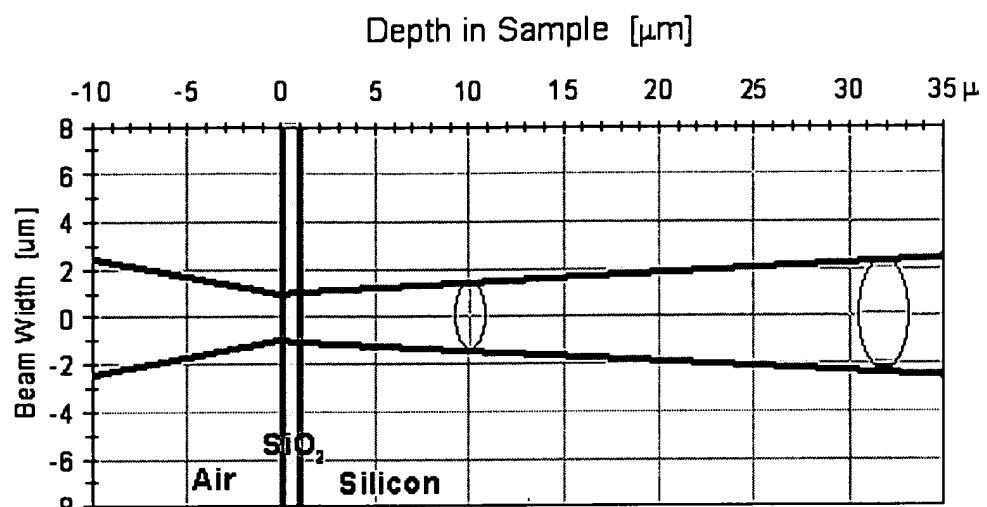


FIG. 2B

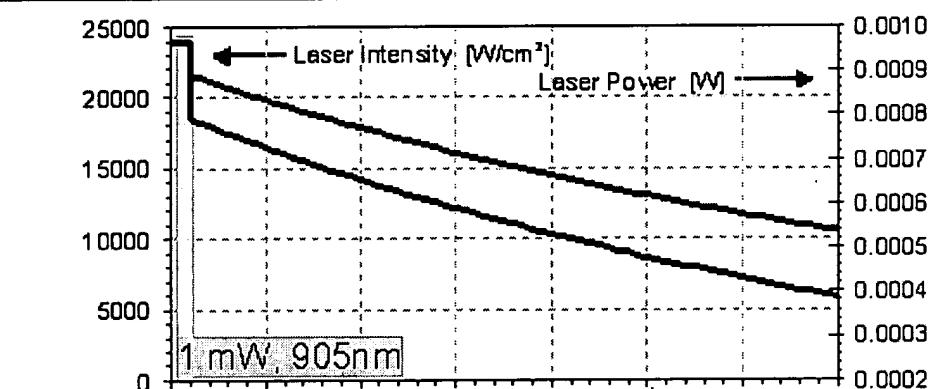
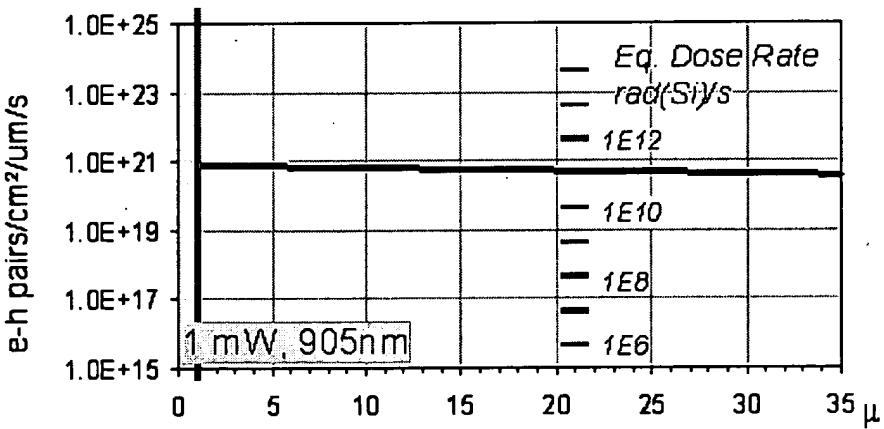


FIG. 2C



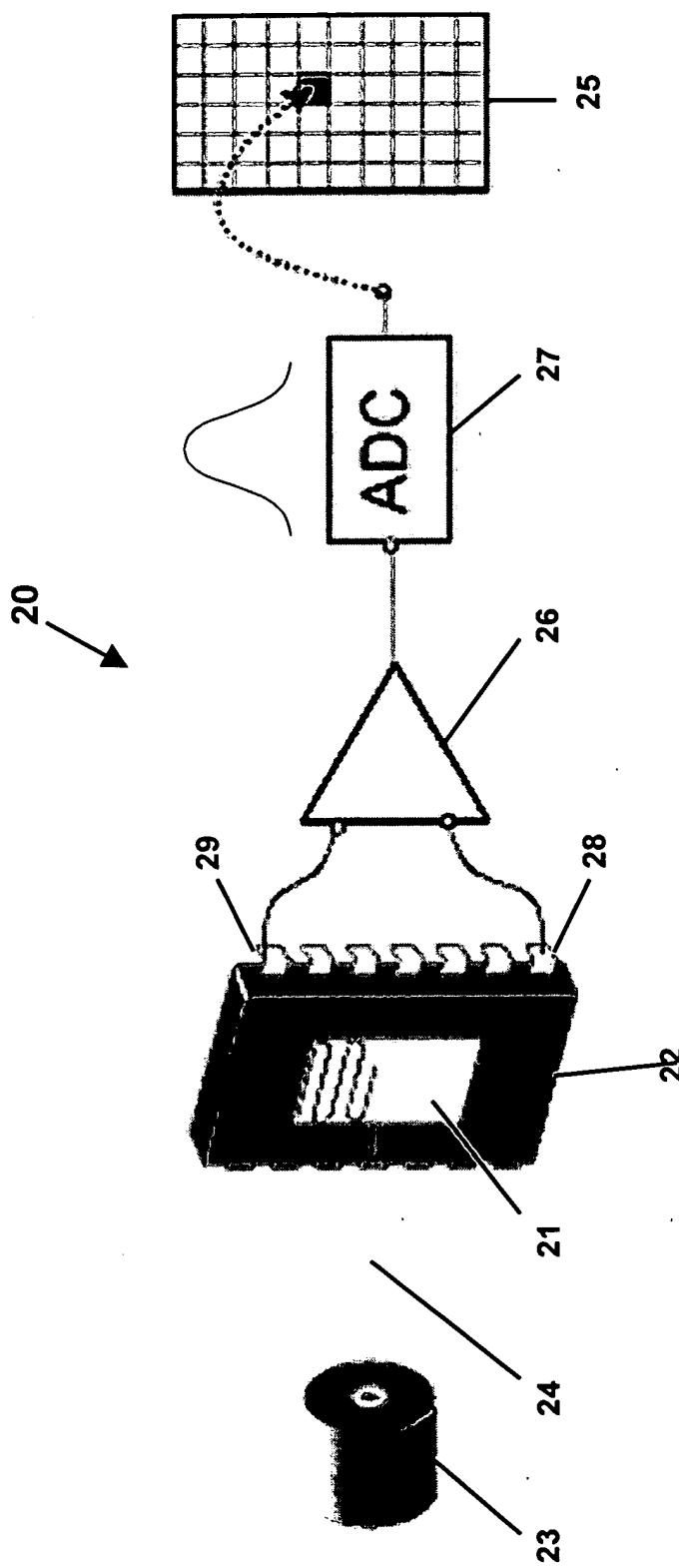


FIG. 3A

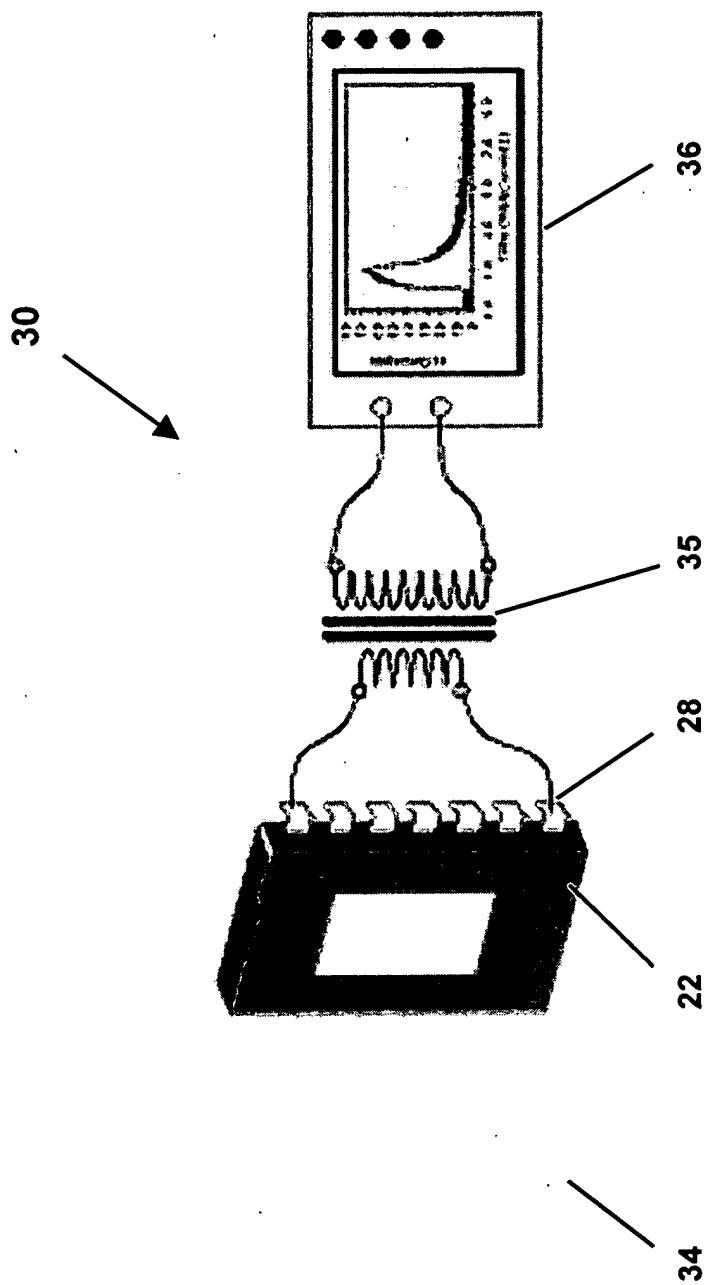


FIG. 3B

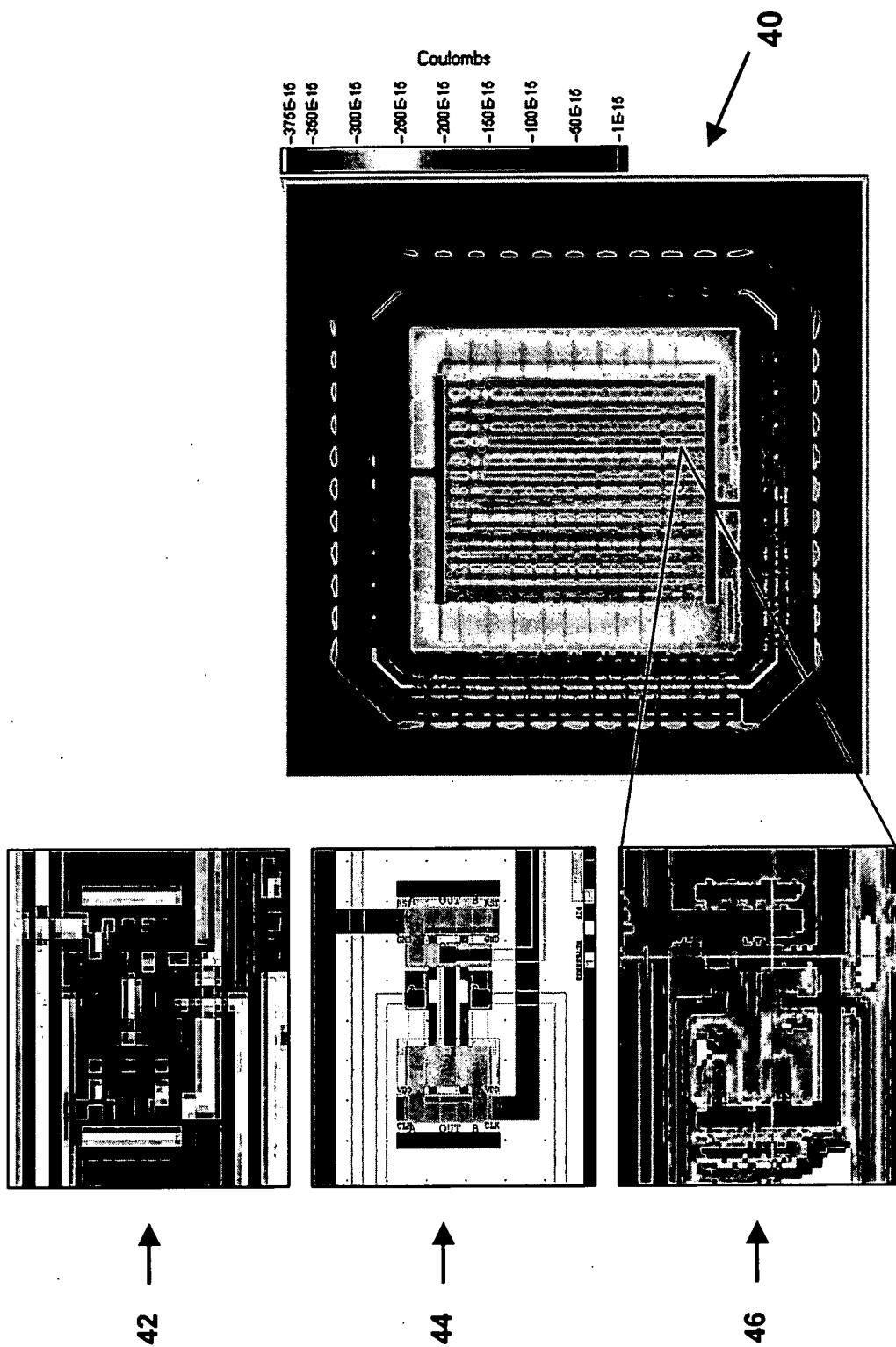


FIG. 4

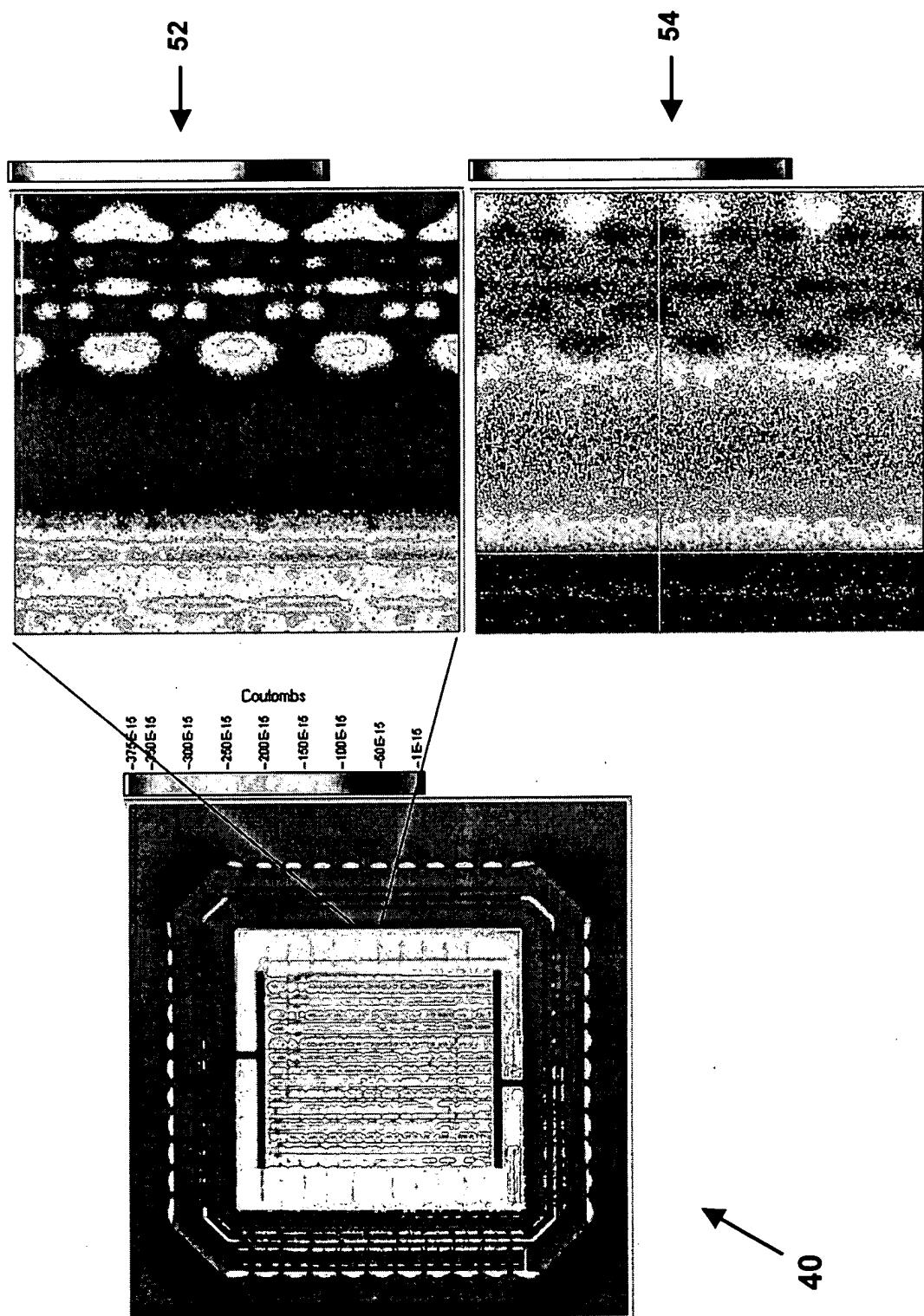


FIG. 5

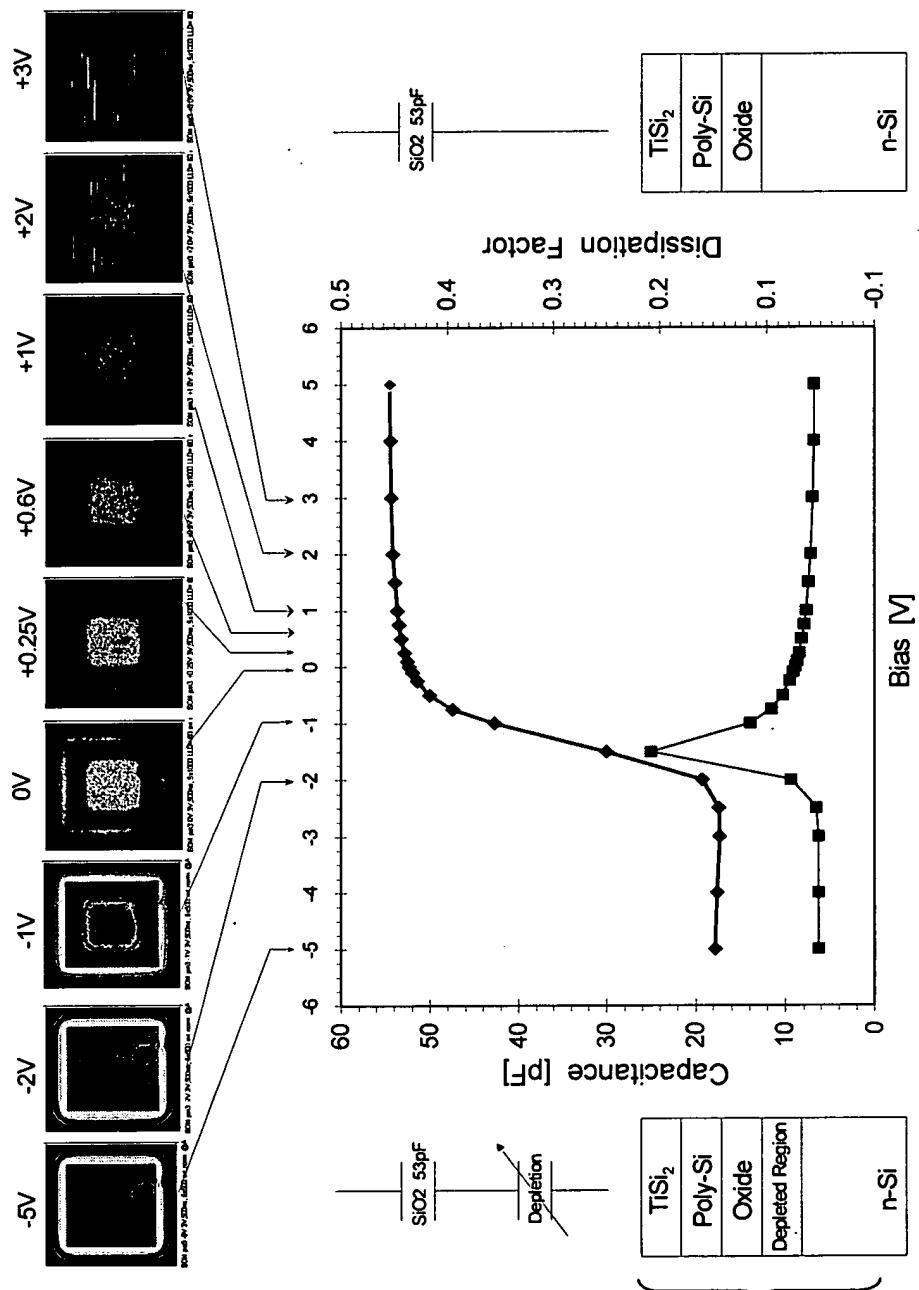


FIG. 6

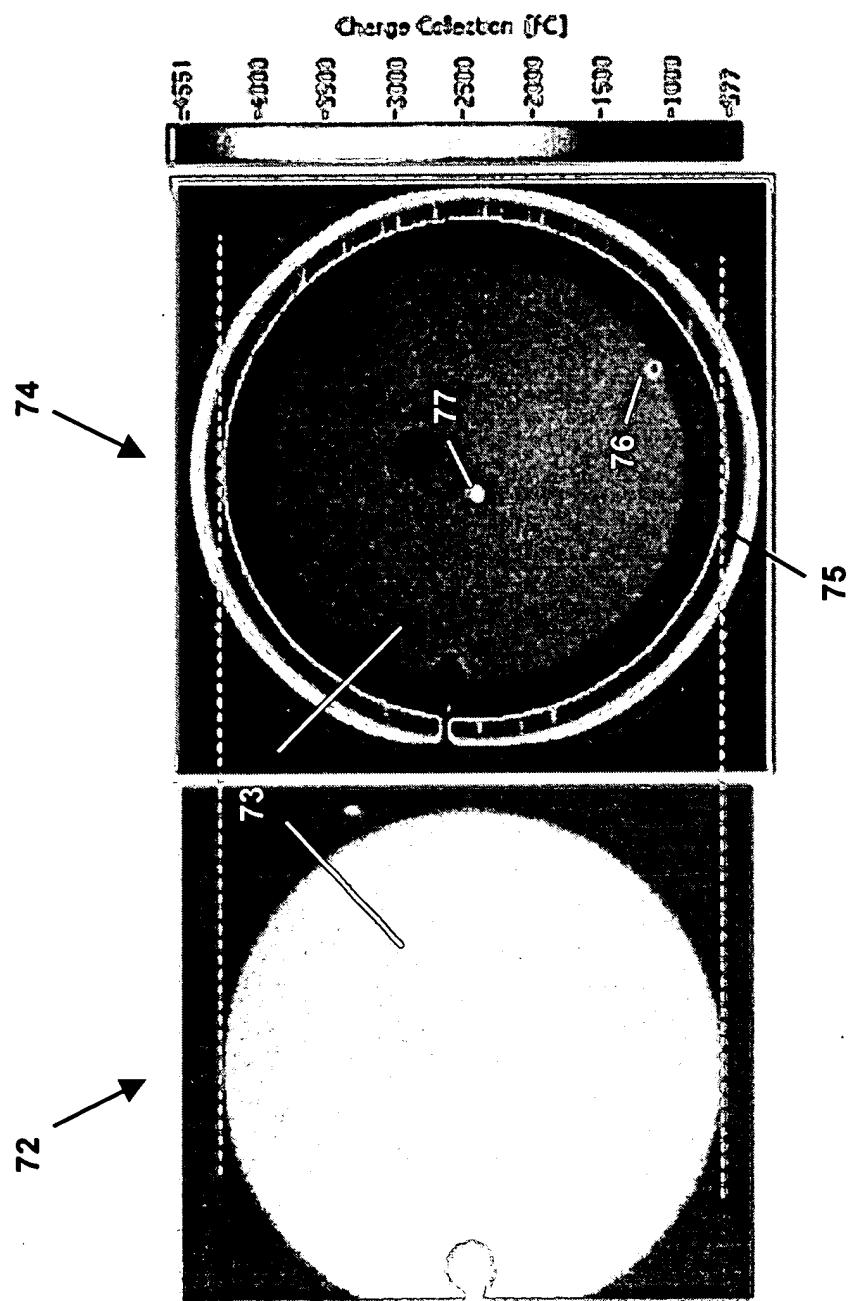


FIG. 7

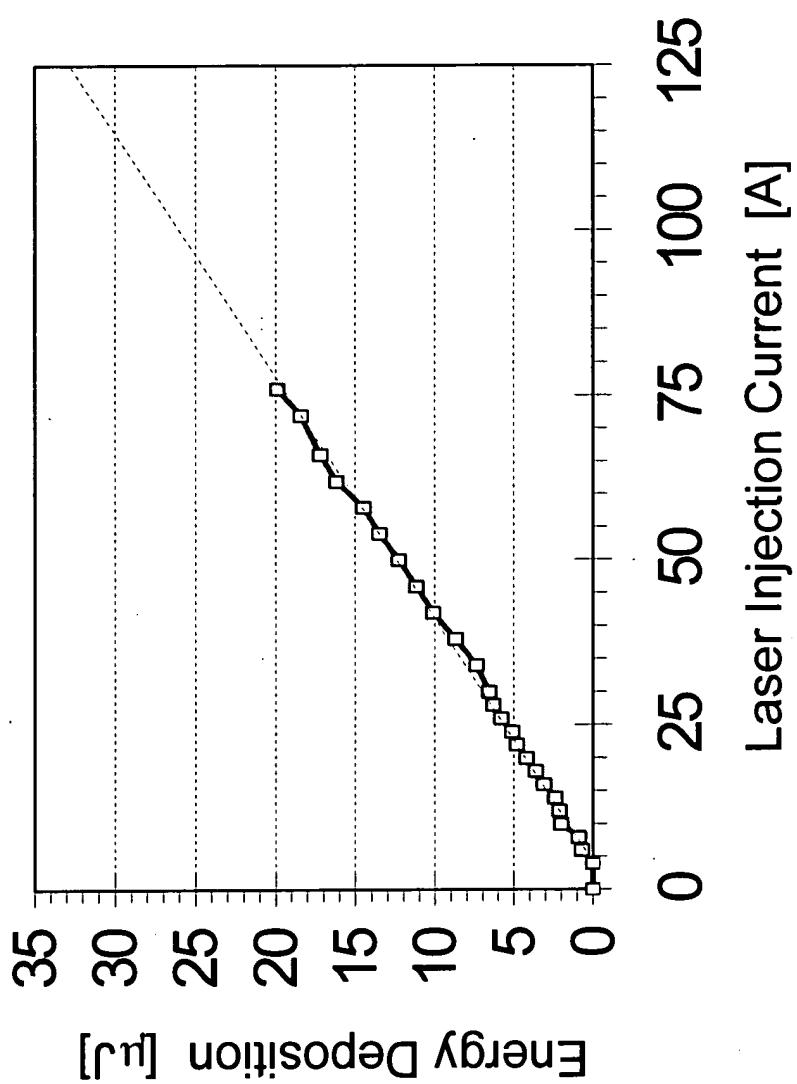


FIG. 8

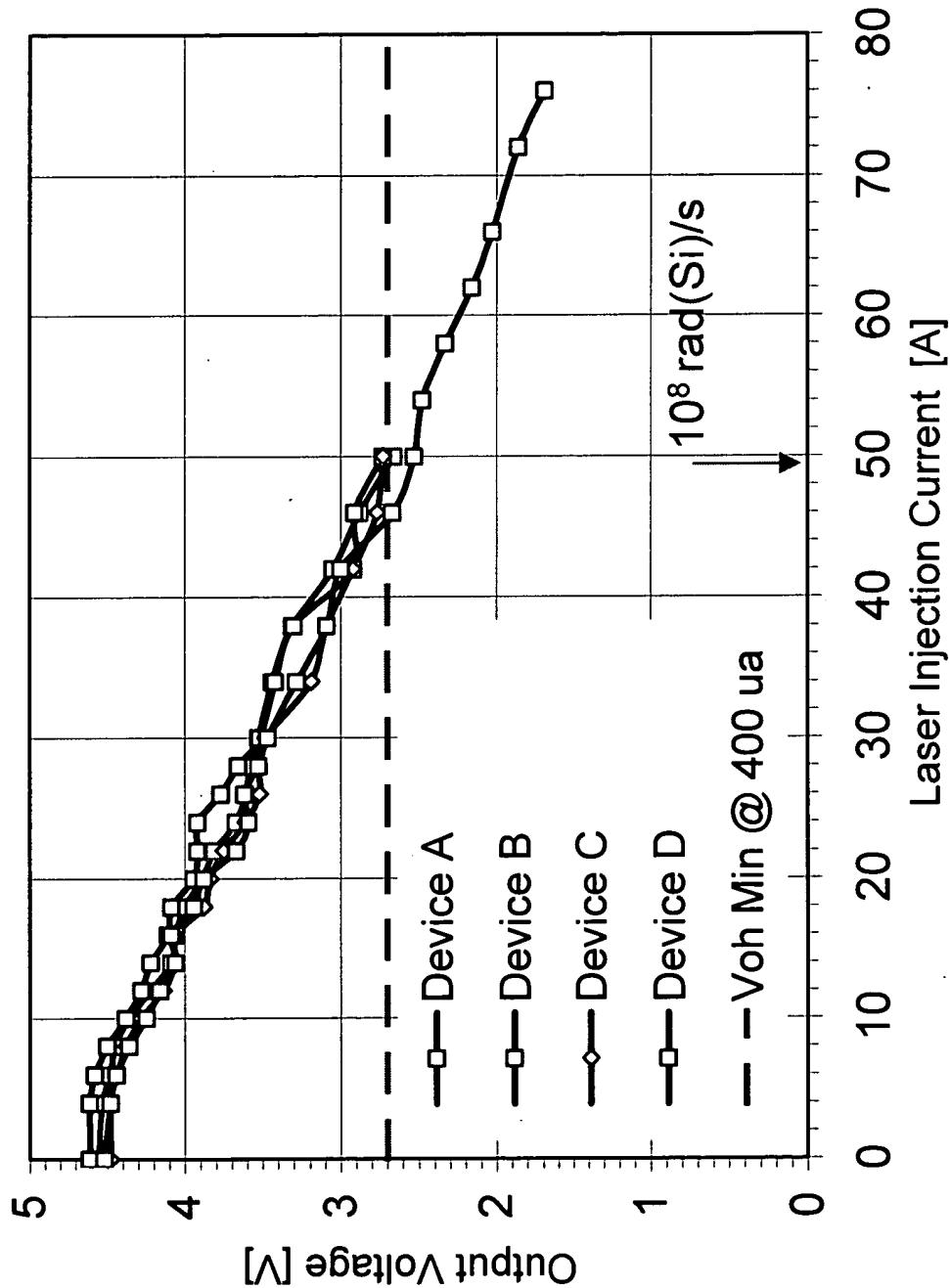


FIG. 9

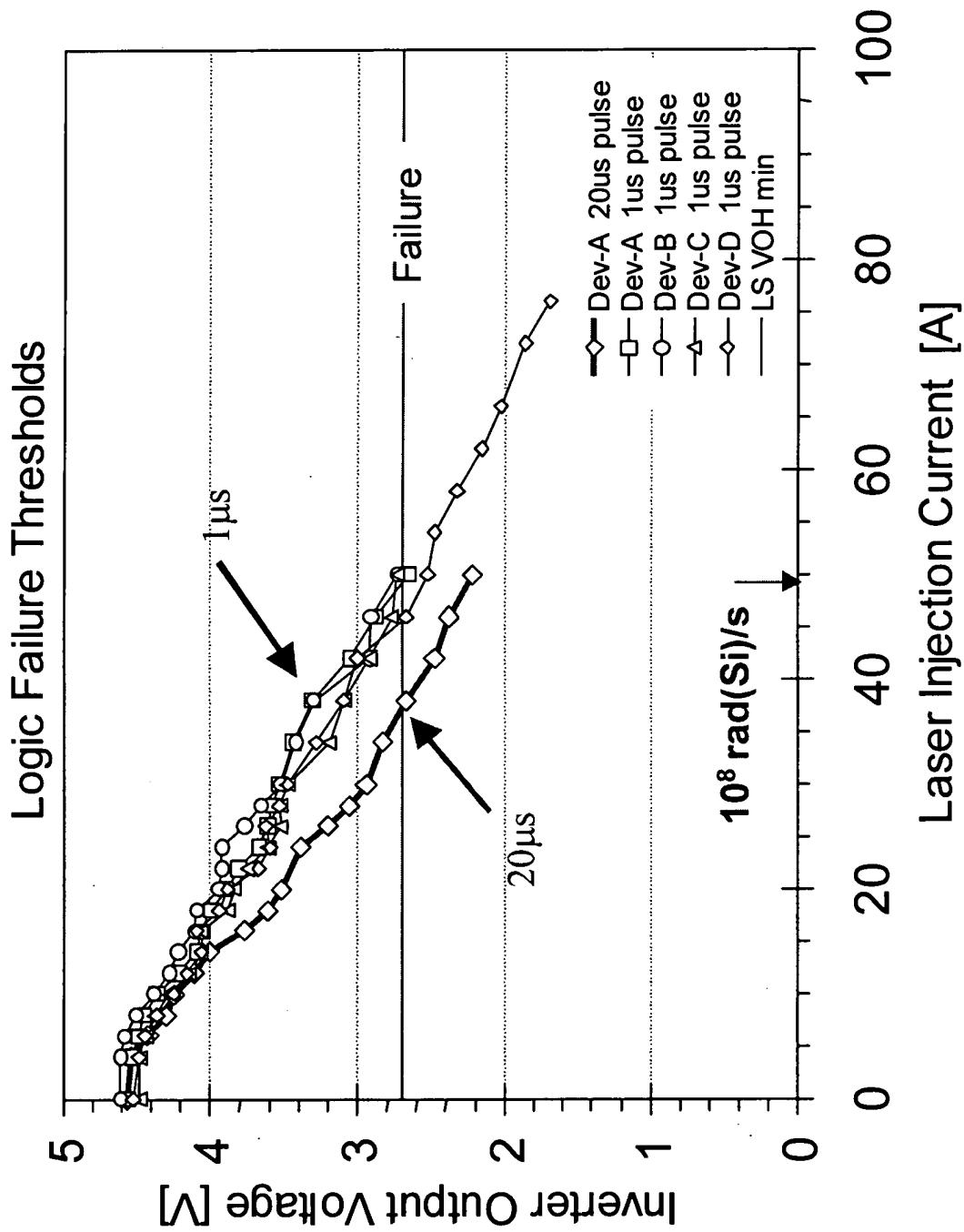


FIG. 10

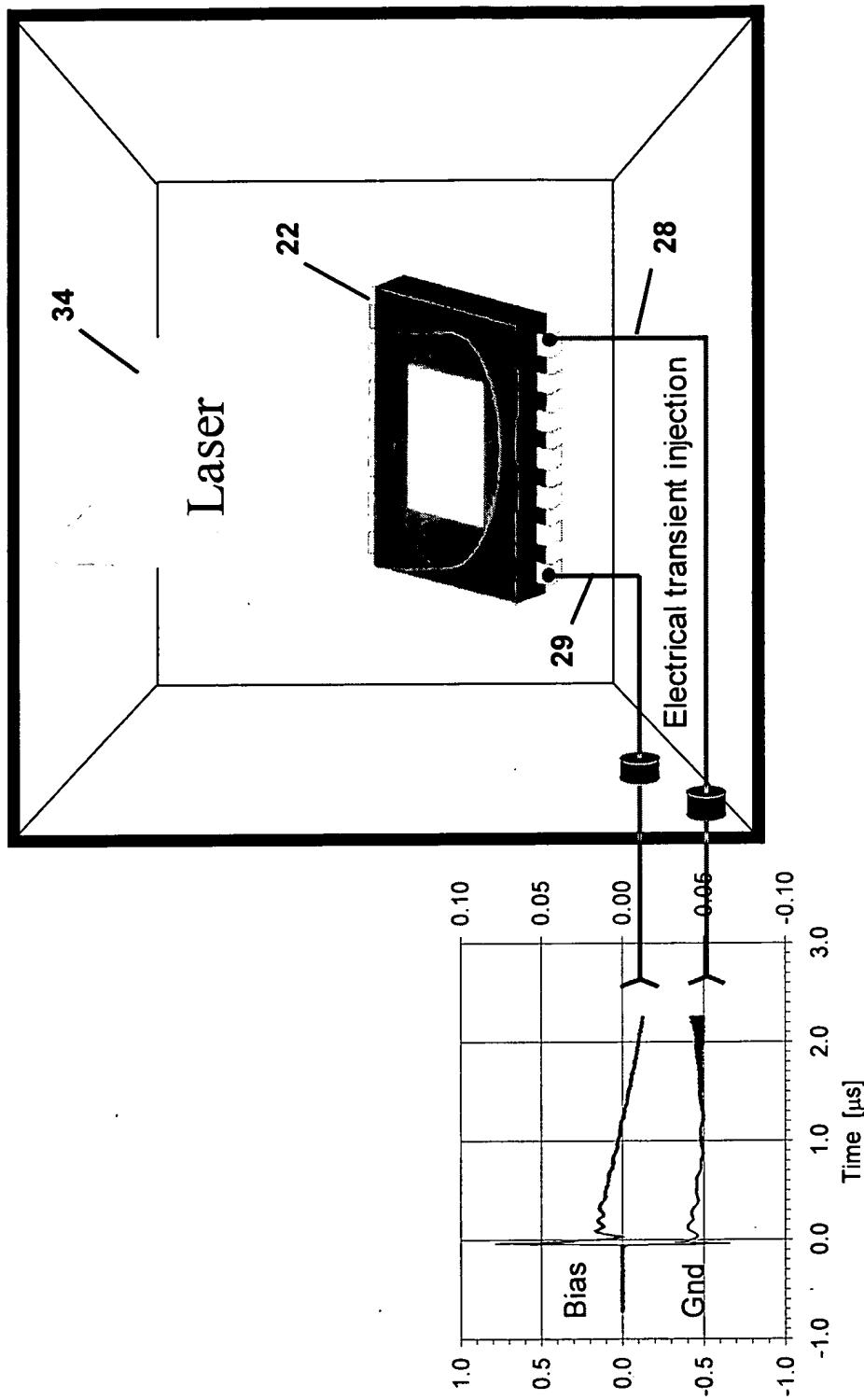


FIG. 11